## Dual N-Channel Enhancement Mode Power MOSFET

## DESCRIPTION

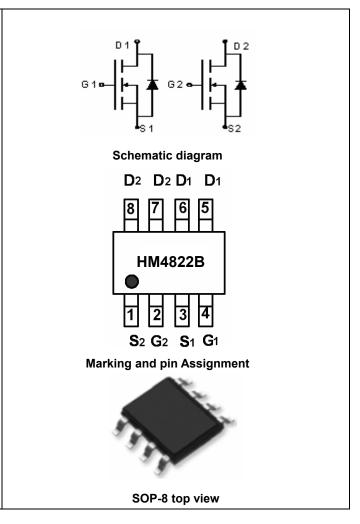
The HM4822B uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

## **GENERAL FEATURES**

- V<sub>DS</sub> =30V,I<sub>D</sub> =10A
  R<sub>DS(ON)</sub> < 11mΩ @ V<sub>GS</sub>=10V
  R<sub>DS(ON)</sub> < 13mΩ @ V<sub>GS</sub>=4.5V
- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current

## Application

- Power switching application
- Hard Switched and High Frequency Circuits
- Uninterruptible Power Supply



## Package Marking And Ordering Information

Device Marking	Device	Device Package Reel Size		Device Device Package Reel Size Tape width		Tape width	Quantity	
HM4822B	HM4822B	SOP-8	Ø330mm	12mm	2500 units			

#### Absolute Maximum Ratings (TA=25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	Vds	30	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current-Continuous	ID	10	А
Drain Current-Continuous(T <sub>C</sub> =100℃)	I <sub>D</sub> (100℃)	6	А
Pulsed Drain Current	I <sub>DM</sub>	50	А
Maximum Power Dissipation	PD	2.5	W
Operating Junction and Storage Temperature Range	T <sub>J</sub> ,T <sub>STG</sub>	-55 To 150	°C

## **Thermal Characteristic**

Thermal Resistance, Junction-to-Case(Note 2)	$R_{ extsf{ heta}JC}$	50	°C/W	
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#### Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit	
Off Characteristics	·····						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250µA	30	33	-	V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V,V <sub>GS</sub> =0V	-	-	1	μA	
Gate-Body Leakage Current	I <sub>GSS</sub>	$V_{GS}$ =±20V, $V_{DS}$ =0V	-	-	±100	nA	
On Characteristics (Note 3)	·····			•			
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	1	1.8	3	V	
Desia Course On State Desistence	D	V <sub>GS</sub> =10V, I <sub>D</sub> =10A	-	9	11		
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A	-	11.5	13	mΩ	
Forward Transconductance	<b>G</b> FS	V <sub>DS</sub> =5V,I <sub>D</sub> =10A	15	-	-	S	
Dynamic Characteristics (Note4)							
Input Capacitance	C <sub>lss</sub>	V <sub>DS</sub> =15V,V <sub>GS</sub> =0V, F=1.0MHz	-	1550	-	PF	
Output Capacitance	C <sub>oss</sub>		-	300	-	PF	
Reverse Transfer Capacitance	C <sub>rss</sub>	F=1.0MHZ	-	180	-	PF	
Switching Characteristics (Note 4)							
Turn-on Delay Time	t <sub>d(on)</sub>		-	30	-	nS	
Turn-on Rise Time	tr	V <sub>DD</sub> =25V,I <sub>D</sub> =1A	-	20	-	nS	
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10V, $R_{GEN}$ =6 $\Omega$	-	100	-	nS	
Turn-Off Fall Time	t <sub>f</sub>		-	80	-	nS	
Total Gate Charge	Qg	)/ _15)/  _104	-	13	-	nC	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> =15V,I <sub>D</sub> =10A, V <sub>GS</sub> =5V	-	5.5	-	nC	
Gate-Drain Charge	Q <sub>gd</sub>	v <sub>GS</sub> =3v	-	3.5	-	nC	
Drain-Source Diode Characteristics			·				
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =10A	-	-	1.2	V	
Diode Forward Current (Note 2)	Is		-	-	10	А	

#### Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.

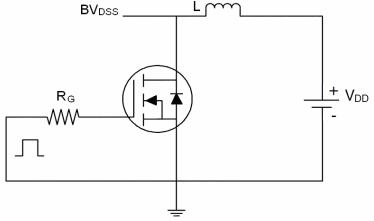
**2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.

**3.** Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2%.

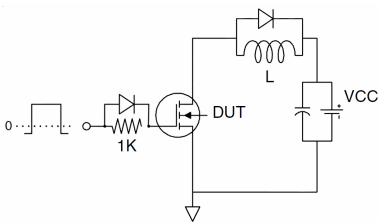
4. Guaranteed by design, not subject to production

# **Test circuit**

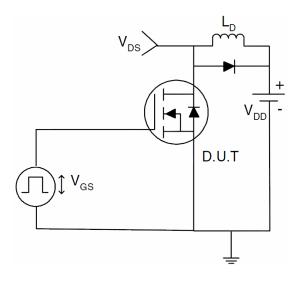
1) E<sub>AS</sub> test Circuits



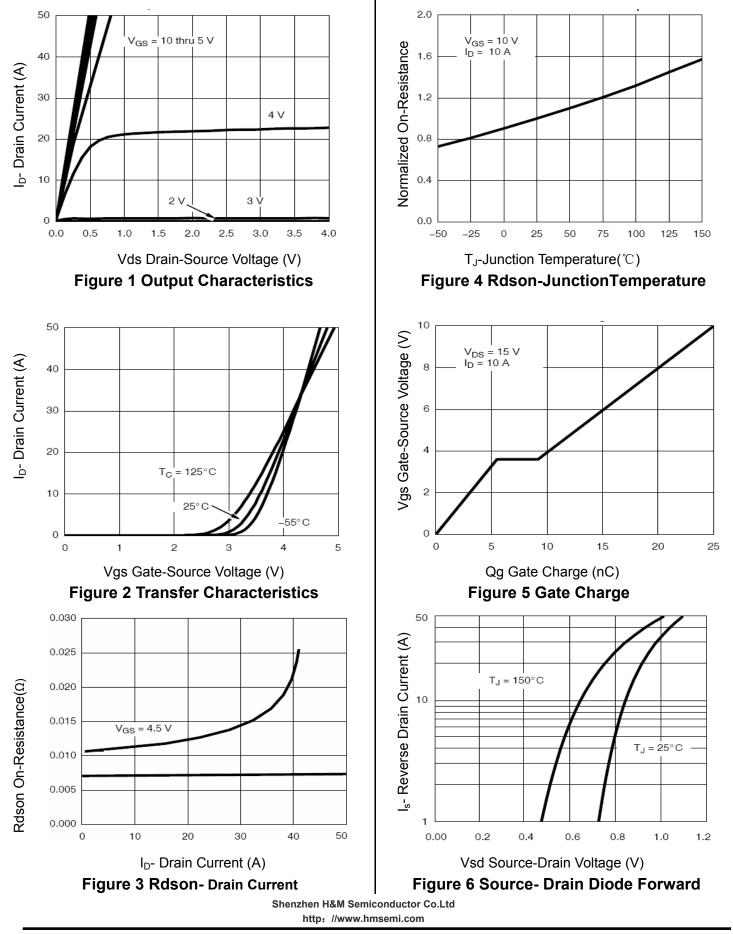
## 2) Gate charge test Circuit:



3) Switch Time Test Circuit:



## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (Curves)





0.02

0.01

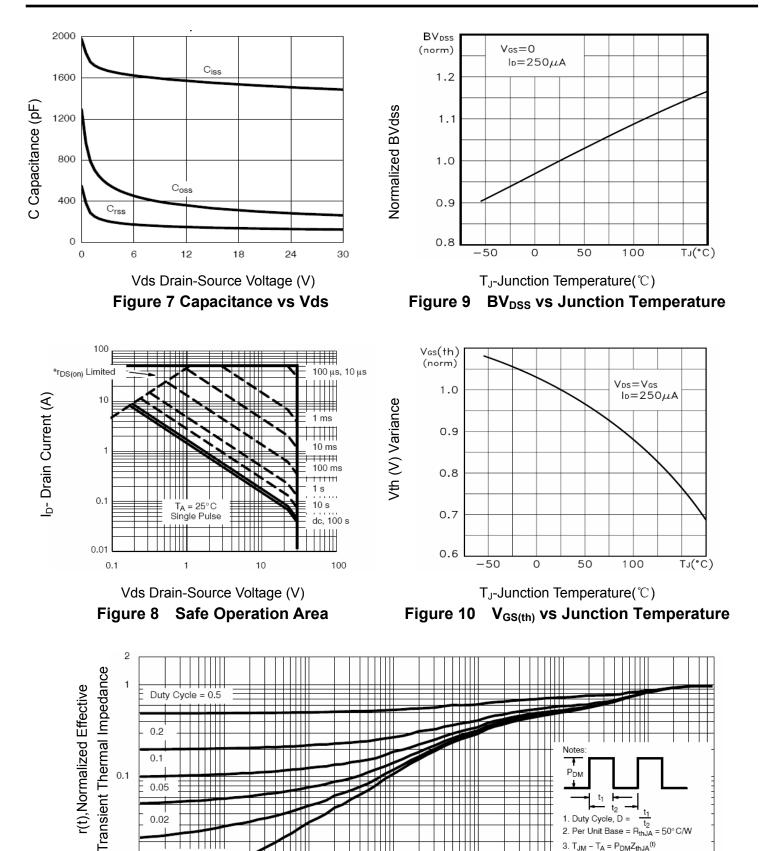
10-4

Single Pulse

1 1 1 1 1 1 1

10-<sup>3</sup>

10-2



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10-1

Square Wave Pluse Duration(sec) Figure 11 Normalized Maximum Transient Thermal Impedance 600

1. Duty Cycle, D =

4. Surface Mounted

10

1

2. Per Unit Base = RthJA

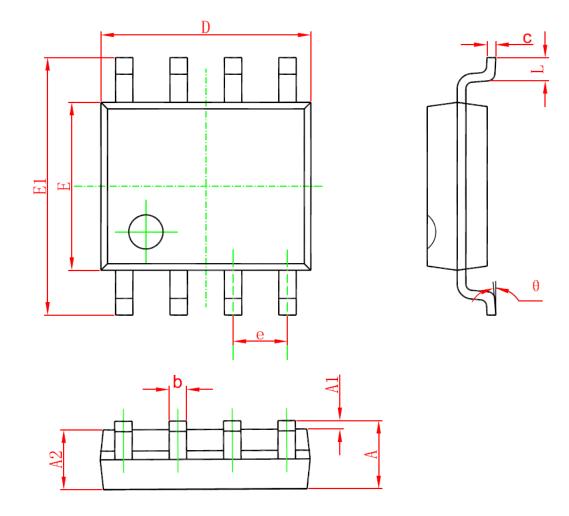
3.  $T_{JM} - T_A = P_{DM}Z_{thJA}^{(t)}$ 

t2

100

= 50° C/W





Cumb a l	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
A	1. 350	1. 750	0. 053	0. 069	
A1	0. 100	0. 250	0.004	0. 010	
A2	1. 350	1. 550	0.053	0. 061	
b	0. 330	0.510	0.013	0. 020	
С	0. 170	0. 250	0.006	0. 010	
D	4. 700	5. 100	0. 185	0. 200	
E	3.800	4.000	0. 150	0. 157	
E1	5. 800	6. 200	0. 228	0. 244	
е	1. 270 (BSC)		0. 050 (BSC)		
Ĺ	0. 400	1. 270	0.016	0. 050	
θ	0°	8°	0°	8°	

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